


<b>Search Notes</b> 	<b>Application/Control No.</b> 10582959	<b>Applicant(s)/Patent Under Reexamination</b> TAKAMATSU ET AL.
	<b>Examiner</b> Stefan Krueer	<b>Art Unit</b> 3654

SEARCHED			
Class	Subclass	Date	Examiner
242	374	06/08/2008	SHK
242	374, 384.2, 384.6	08/29/2009	SHK

SEARCH NOTES		
Search Notes	Date	Examiner
PLUS	06/08/2008	SHK
Application having common co-inventor(s)s		
Backward/forward citations of prior art	12/04/2008	SHK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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